

Using the SPENVIS SEE Tools

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Introduction

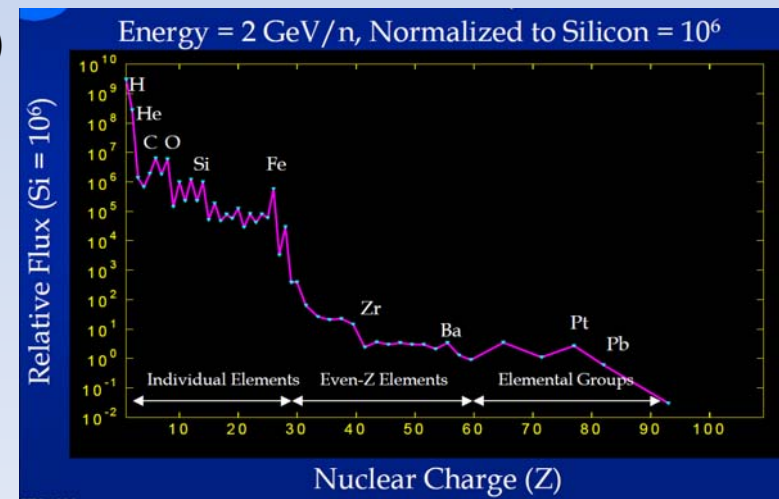
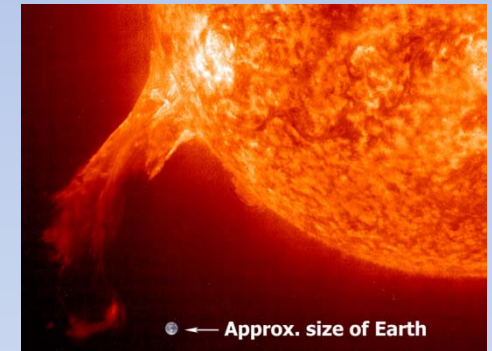
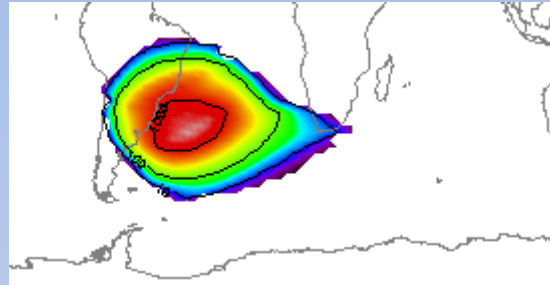
- The SPENVIS SEE tools:
 - LETORB: calculates LET and proton spectrum
 - UPSETO: calculates SEE upset rates from LET & p⁺ spectrum
- These require as inputs:
 - Orbit
 - Trapped protons (optional)
 - Future implementation: more complex solar proton spectra (flux, fluence, PSYCHIC, etc)
 - Device parameters (from test data, etc.)

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- Required outputs:
 - Total mission SEE rates: used in s/c design for part selection and data correction. Applicable to all subsystems on the s/c.
 - Non-destructive: rate specified by design (EDAC, etc.)
 - Destructive: $1/\text{rate} \gg \text{operational time}$.
 - Worst case SEE rates: used in s/c design for part selection and mitigation. Applicable to critical subsystems on the s/c.
 - Non-destructive: used to specify operational constraints
 - Destructive: risk of event accepted by project.
 - Global SEE rates for operational uses for risk mitigation.

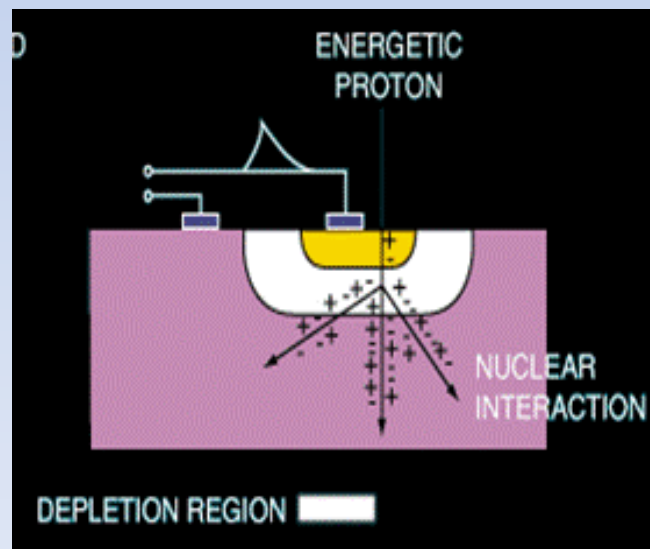
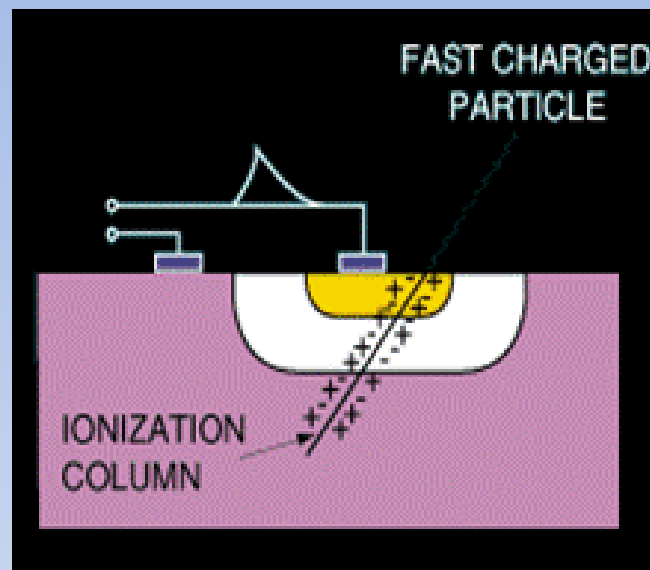
Environment Sources

- Sun Synchronous Orbit
 - Trapped Protons
 - AP8MAX
 - AP8MIN
 - Solar Protons
 - Included in LETORB (CREME-86/M8)
 - Future: CREME-96 worst case models.
 - Future: will be derived from Solar Proton models as well (ESP/PSYCHIC)
 - Geomagnetic shielding
 - Cosmic Rays
 - CREME-86 models (M=3, M=1)
 - ISO-15390 model (ECSS-E-ST-10-04C standard)
 - Geomagnetic shielding
- Shielding:
 - Generally assume 1 g/cm^2 of spherical shielding.
 - SEE calculations are generally stable with shielding (penetrating particles) over s/c shielding range.



Upset Calculation - Theory

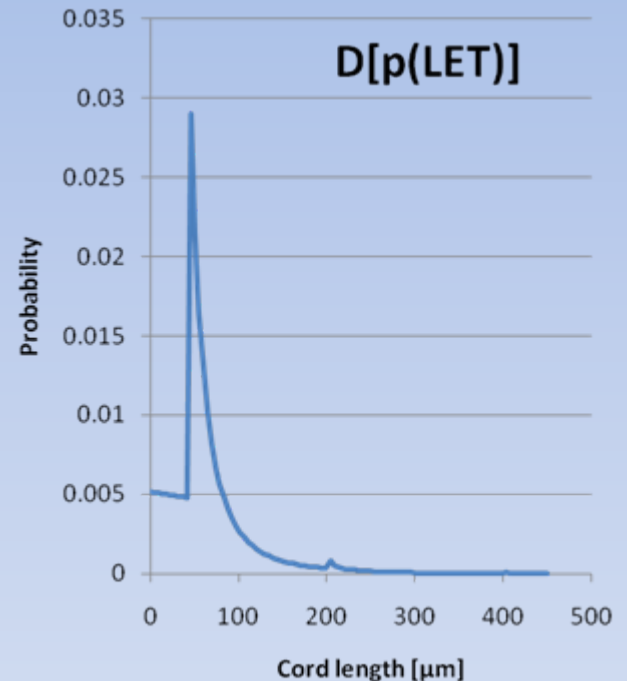
- Ions: cause upsets via ionization; this depends on the length of the ionization column in the sensitive volume of the component.
- Protons: cause upsets via a nuclear interaction leading to an ionization column.



Upset Calculation - Ions

- CREME 86/96 RPP method:
 - Device Dimensions ($l \times w \times h$) \rightarrow RPP path length distribution. These dimensions are derived from actual device dimension measurements, the cross section test data and device thickness.
 - Critical Charge (Q_c) – proportional to LET_{th} .
 - Cross section: is from the device test data.

In this analysis, the critical charge was derived from a parametric study of on-orbit experience (MTBF).



$$SEUrate(\# / bit - s) = 22.5 \pi \sigma Q_{crit} \int_{22.5 Q_{cri} / p_{max}}^{LET_{max}} \frac{D[p(LET)] f(LET)}{LET^2} dLET$$

N.B.: 22.5 is for Silicon, for GaAs this becomes 30.0

Upset Calculation - Theory

- Protons: CREME 86/96 method:
Cross-section data (Bendel, Weibull, Profit)

In principle, there are no angular effects to consider.

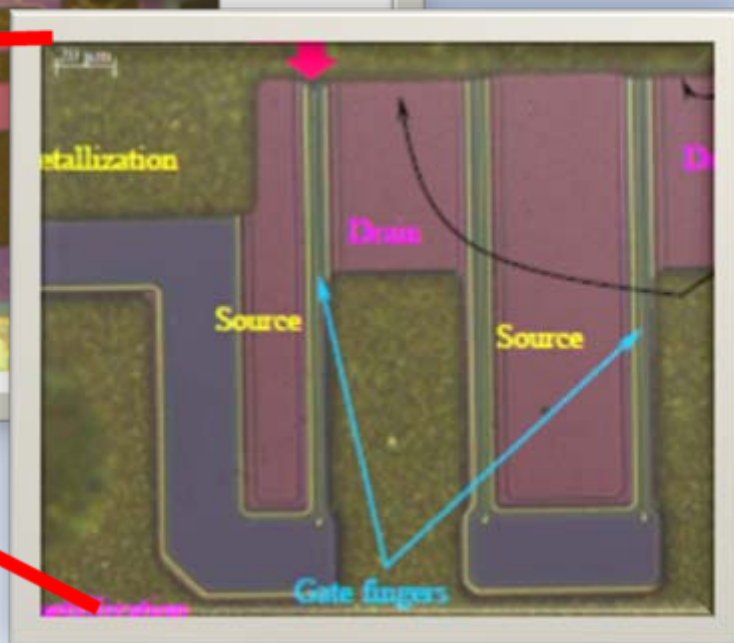
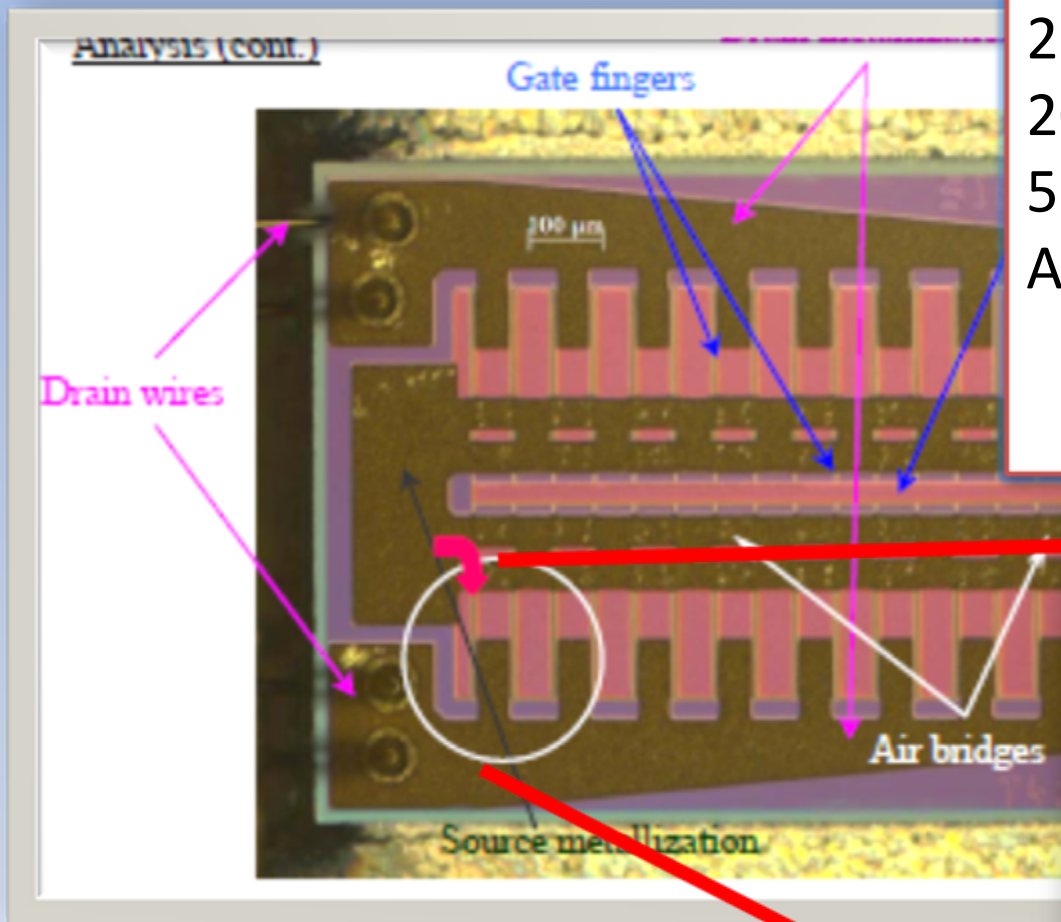
$$SEERate = \int f(E)\sigma(E)dE$$

The Analysis

- Calculate the LET and proton spectra (LETORB)
- Determine device characteristics
- Calculate upset rates from trapped protons, solar particles and GCRs (UPSET)

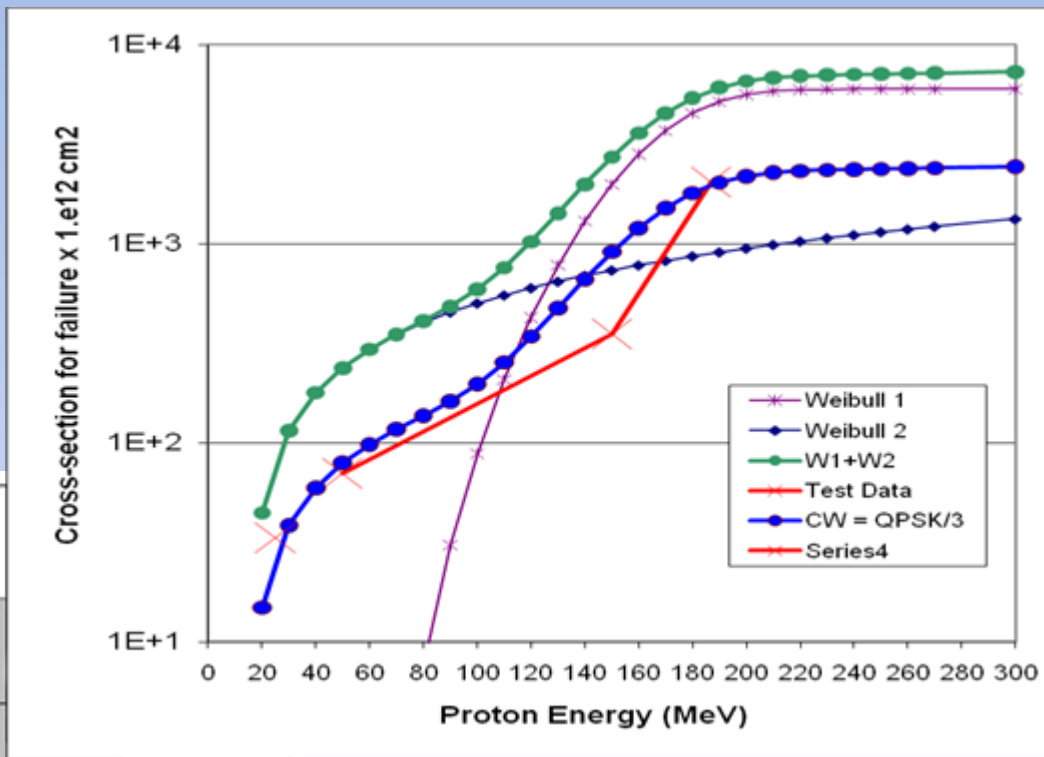
Device Dimensions

2 devices
 20 "fingers"
 5 μm × 200 μm Gates
 Active area:
 $400 \times 200 \mu\text{m}^2 = 8 \times 10^{-4} \text{ cm}^2$

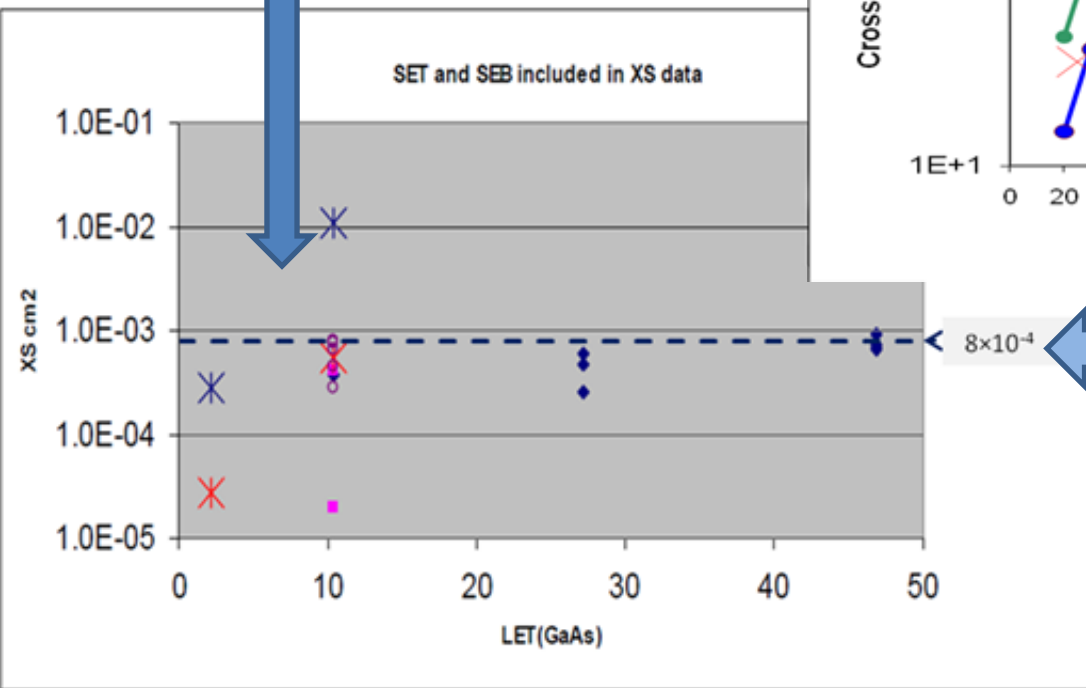
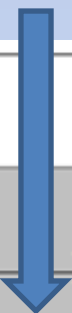


Device Test Data

Proton test data



No obvious LET_{th}



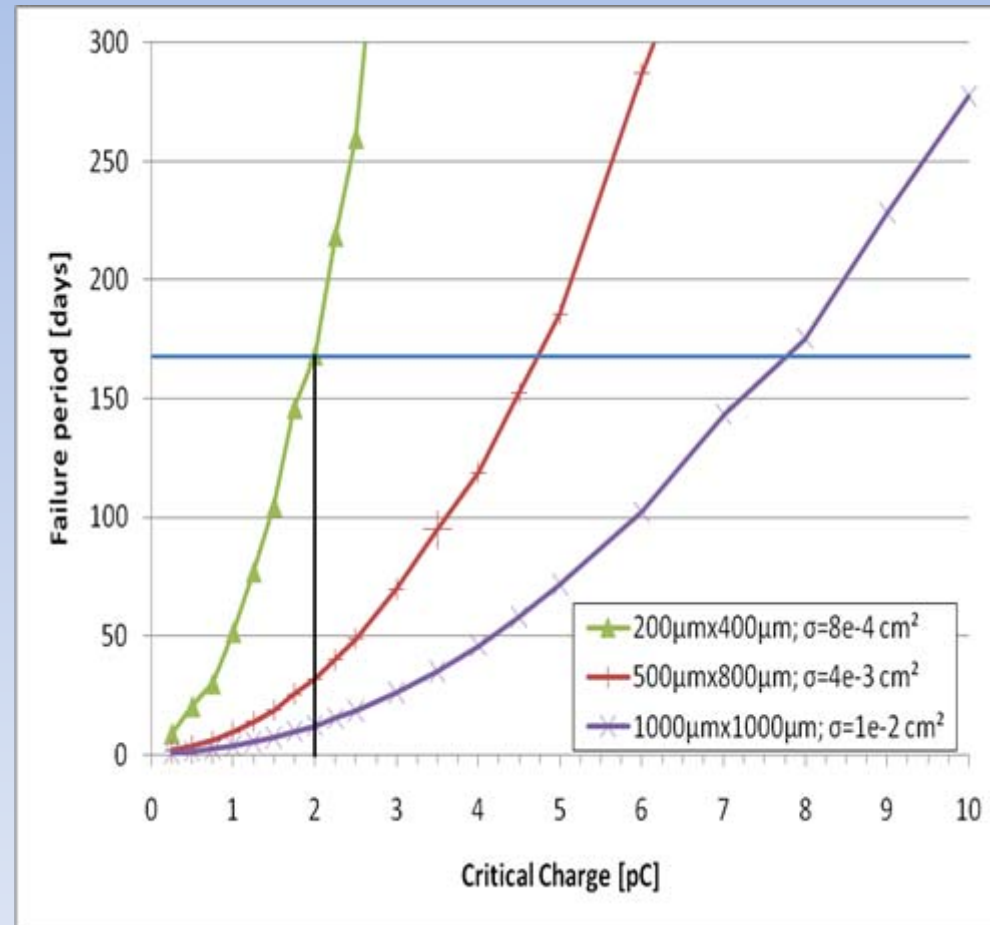
8×10^{-4}

Test saturation cross section matches the visual inspection

Heavy Ion test data

UPSET device parameters

- Ion Rates:
 - Device dimensions calculated from visual inspection and cross section of test data ($42\mu\text{m} \times 400\mu\text{m} \times 200\mu\text{m}$).
 - Critical charge (2 pC) was derived from a parametric analysis based on the on-orbit experience; poor definition of the LET_{th} provides values from $2 - 10\text{ MeV cm}^2/\text{mg}$
- Proton Rates:
 - It was decided that a double Weibull fit was the best form for the proton data – to capture the Knee.



SPENVIS LET Calculation

Radiation sources and effects: Ion energy and LET spectra model parameters - Mozilla Firefox
http://www.spennis.oma.be/htbin/spennis.exe/SSO?%23resetToPrevious(letorb_par.html)

SPENVIS Project: SSO
Radiation sources and effects
Ion energy and LET spectra: Input parameters

Output
Help

UP


Target material: GaAs (SRIM2008) ▾

Shielding thickness (Al equivalent): 1 g/cm2 ▾

Ion range: H ▾ to Ni ▾

Galactic cosmic rays model: ISO-15390 standard model ▾

Model developed by



Solar activity data: Solar Minimum (May 1996) ▾

Geomagnetic shielding: apply ▾ for quiet ▾ magnetosphere

Trapped protons: taken into account ▾

Output resolution: spectra for each orbital point ▾

Reset Run Combined Run

© ESA

Done

SPENVIS Upset Calc.

To process the double Weibull fit for the proton upsets, we used two devices, one for each fit and then added the results.

Device: user defined

Device name: 400x200, 2pC

Direct ionisation upset rates

Sensitive (GaAs) volume

Shape: rectangular parallelepiped

Dimension [μm]: 400 x 200 x 42

Cross-section method: critical charge

Critical charge [pC]: 2

NOTE: LET curve has been calculated for GaAs.

Proton induced upset rates

Cross-section method: Weibull function

S: 4.77

E_0 [MeV]: 50.0

W [MeV]: 120.86

σ_{lim} [cm^2/bit]: 2e-9

Reset Save

Device: user defined

Device name: 400x200, 2pC-W2

Direct ionisation upset rates

Sensitive (GaAs) volume

Shape: rectangular parallelepiped

Dimension [μm]: 0.01 x 0.01 x 0.01

Cross-section method: critical charge

Critical charge [pC]: 500

NOTE: LET curve has been calculated for GaAs.

Proton induced upset rates

Cross-section method: Weibull function

S: 0.87

E_0 [MeV]: 15

W [MeV]: 1391.86

σ_{lim} [cm^2/bit]: 2e-9

Reset Save

Number of gallium-arsenide devices: 2

Device 1: defined	400x200, 2pC (GaAs) size: 400 x 200 x 42 direct ioniz.: critical charge indirect ioniz.: Weibull function	edit
Device 2: defined	400x200, 2pC-W2 (GaAs) size: 0.01 x 0.01 x 0.01 direct ioniz.: critical charge indirect ioniz.: Weibull function	edit

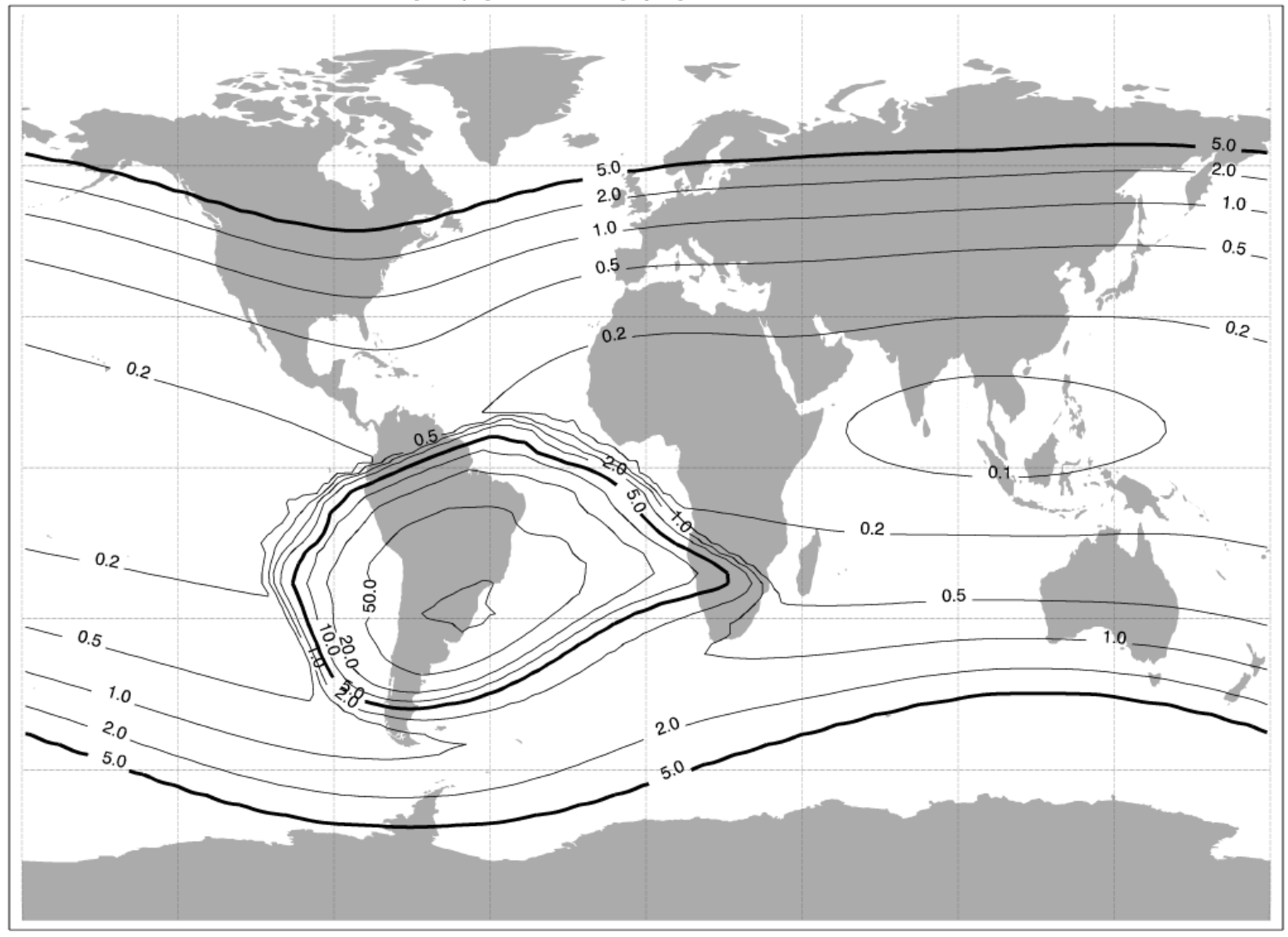
Advanced settings

constant LET across the entire sensitive volume

Reset Run Combined Run

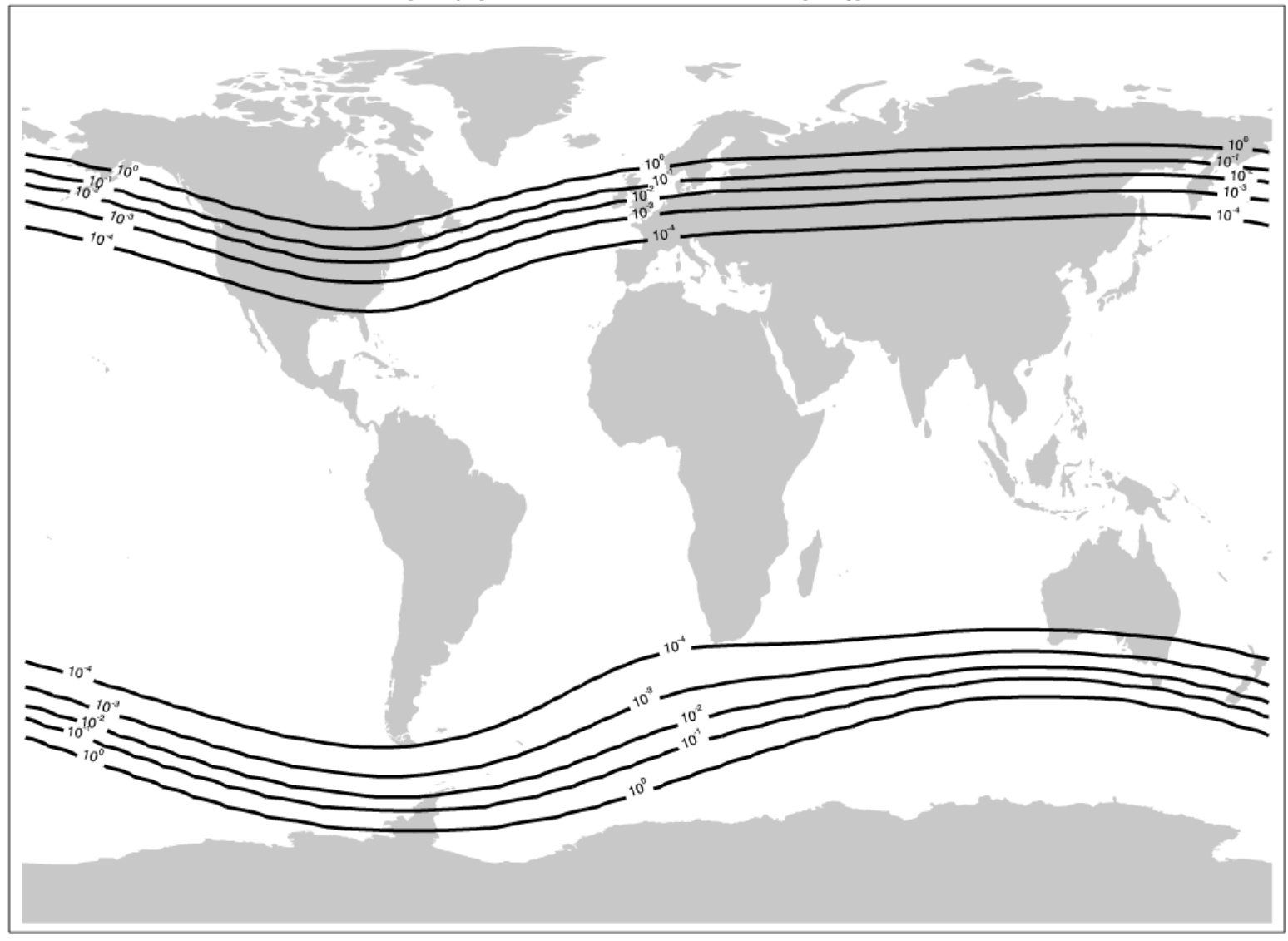
Post Processed results.

GCR and Trapped proton rates – Nominal case



Post Processed results.

Solar Energetic Particle rates – worst 5 minute case



Validation Analysis

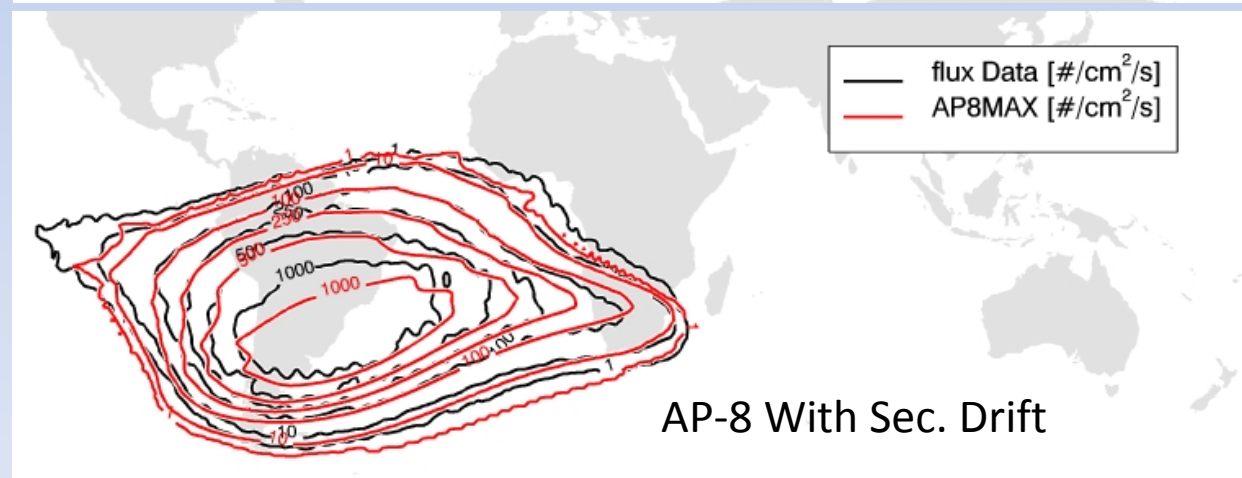
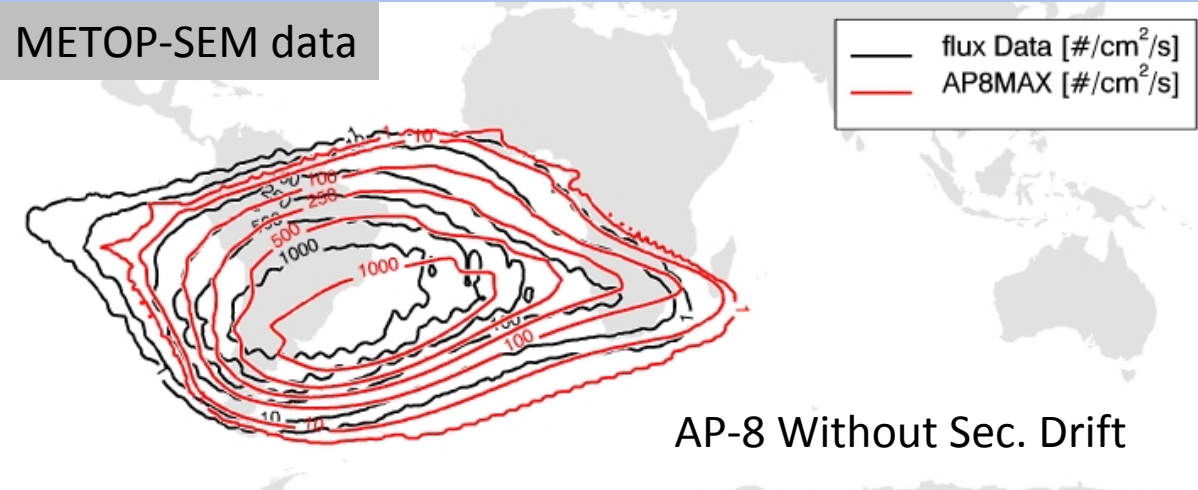
- Trapped protons:
 - Which model is more appropriate:
AP-8 MIN or MAX?
 - Secular drift of the SAA
- Geomagnetic shielding

Validation: Trapped p^+

Secular drift:

south Atlantic Anomaly has shifted West since AP-8 was created (1965).

TREND study showed a 0.3° Westward drift.

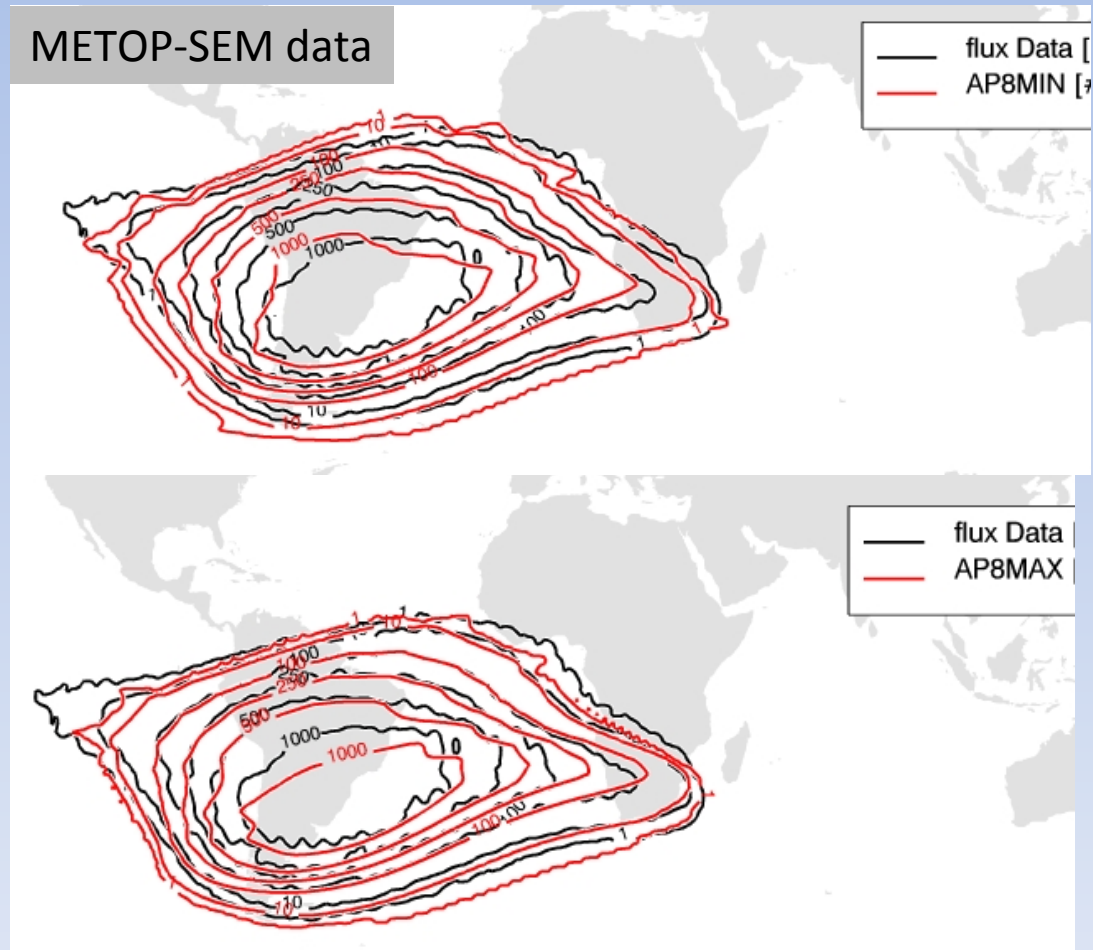


N.B. Energy range is $70 \rightarrow 140$ MeV, the critical range for this component.

Validation: Trapped p^+

Does the magnitude of the AP-8 models fit the data?

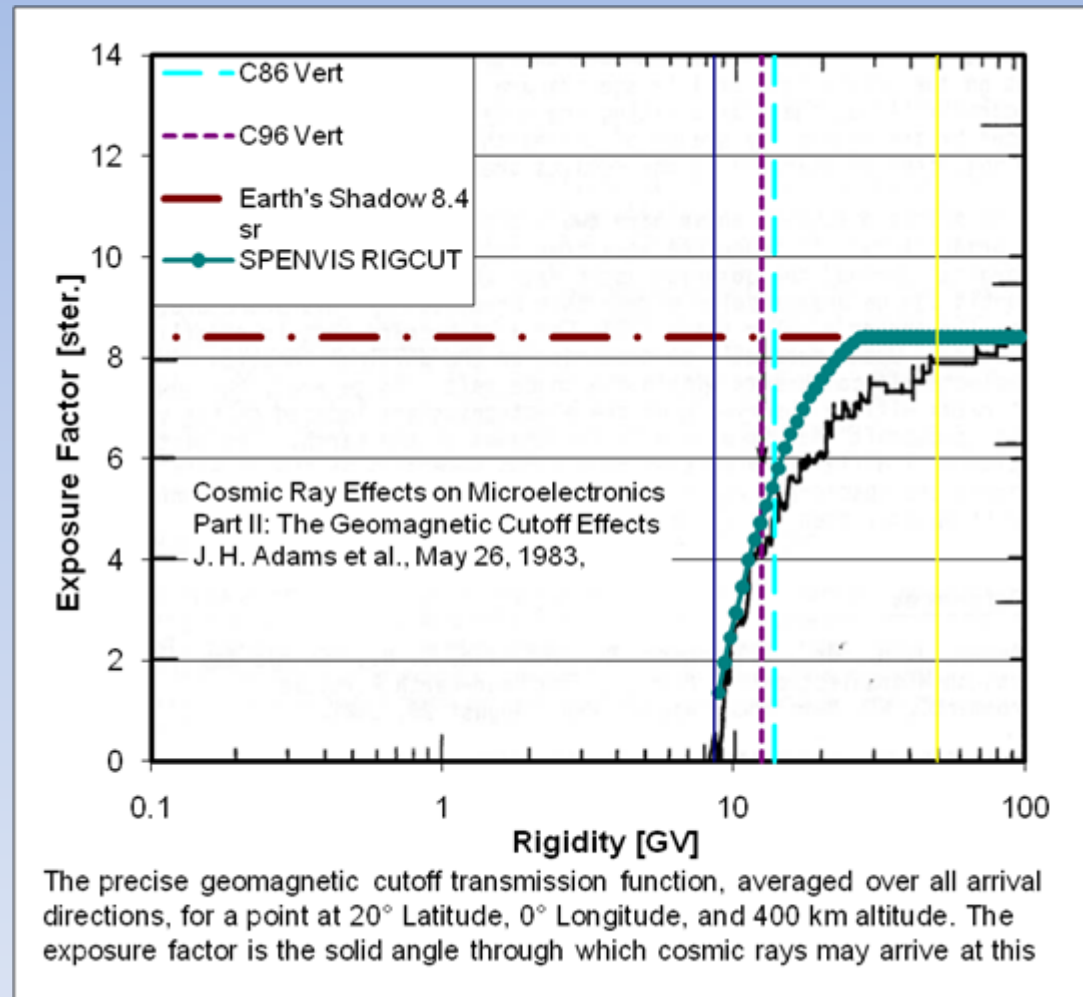
- Contours of MAX match better than MIN, but peak values in the centre are better matched by MIN
- Geographic extent of MAX agrees with METOP SEM data.



N.B. Energy range is 70 → 140 MeV, the critical range for this component.

Validation: Geo Shielding

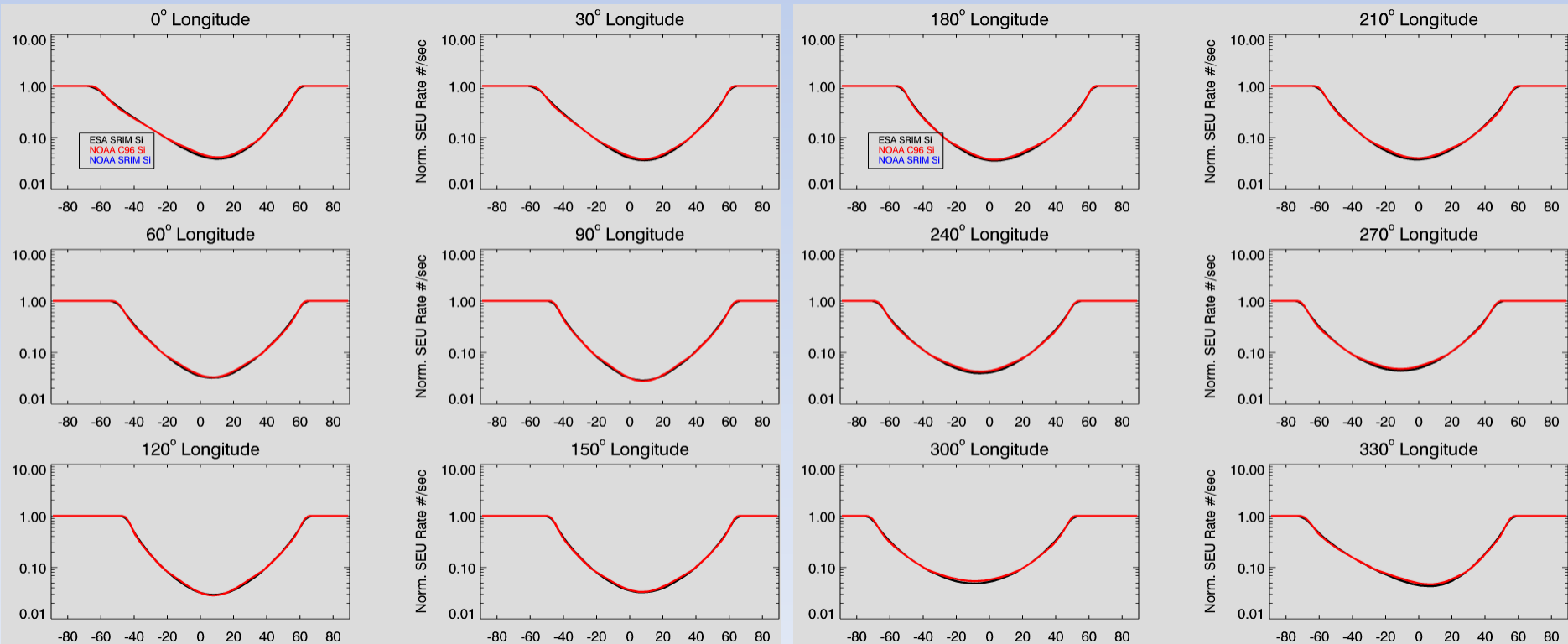
- SPENVIS provides an average over the look direction.
- CREME96 uses a simplified form for vertical arrival.



$$SPENVIS : P_c = \frac{M \cos^4 \lambda}{R^2 \left[1 + \sqrt{1 - \cos \zeta \cos^3 \lambda} \right]^2} \quad \text{Vs.} \quad CREME 96 : P_c = \frac{14.5}{L^2}$$

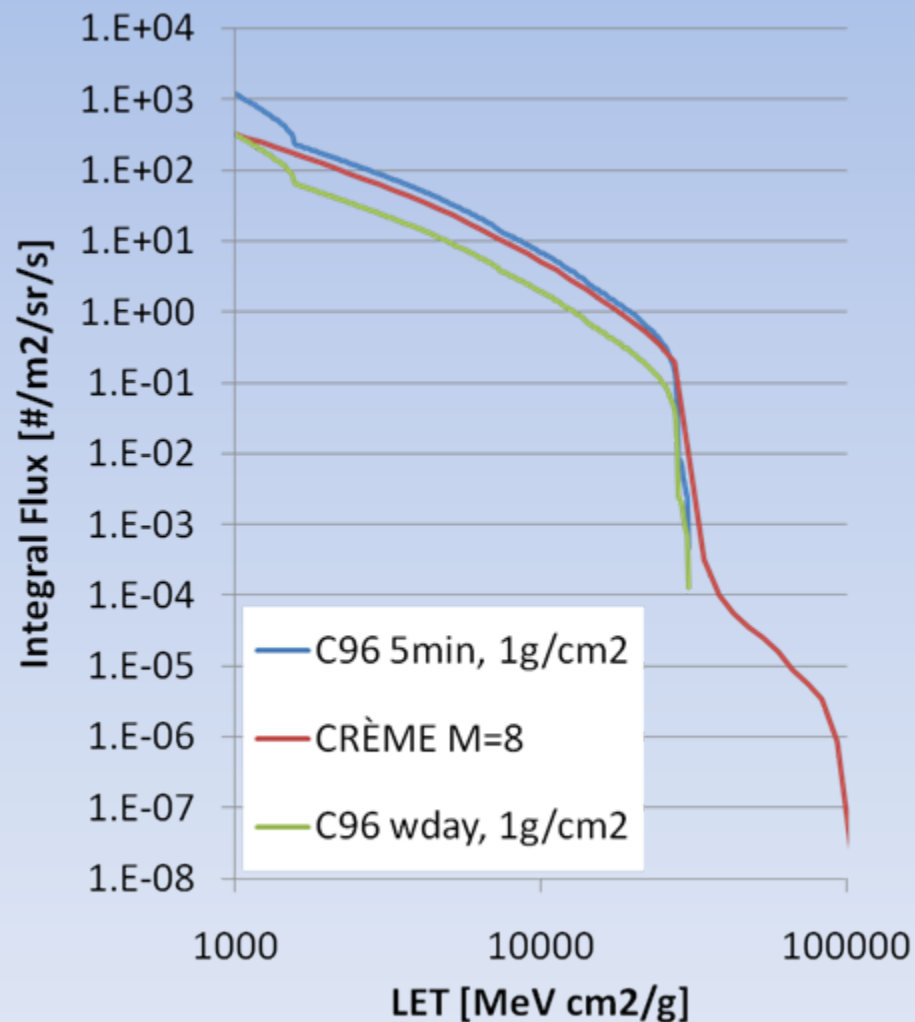
Validation of Geomagnetic Shielding – CREME96

- The IGRF field model was added to the SPENVIS LETORB model, for comparison with CREME-96 and to provide more geographically representative shielding.



Solar Energetic Particles

- Added CREME-96 ion spectra to LETORB:
 - Worst 5-minute
 - Worst day
 - Worst week
- These are the ECSS-E-ST-10-04C required models.



Conclusions

- Upset rates for both Heavy ions, trapped protons and solar particles calculated and geographic maps created for operational risk mitigation.
- AP-8 MAX showed better agreement with data in the required energy range and phase of the solar cycle than MIN.
- Implemented IGRF model for Geomagnetic shielding and validated against CREME-96.
- Implemented CREME-96 worst case solar particle spectra.
- NOTE: the next generation of methods to calculate SEE will become very complex (Monte-Carlo analyses, etc.) and will require a similarly complex user interface – this will be a challenge for the web engineer.